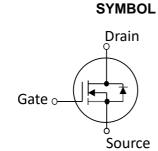


## SPQ1RN100WP

## 100V N-Channel MOSFET

- Advanced Split Gate Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking



Electrical Characteristics in C/P Test (TJ at 25 °C)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	100		_	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	0.8	1.0	mΩ	$V_{GS} = 10V, I_{D} = 1A(1)$
V <sub>GS (th)</sub>	Gate Threshold Voltage	2		4	V	$V_{DS}$ = $V_{GS}$ , $I_D$ =250 $\mu$ A
I <sub>DSS</sub>	Drain-to-Source Leakage Current	_		1	μA	$V_{DS}$ =100V, $V_{GS}$ =0V
I <sub>GSS</sub>	Gate-to-Source Leakage Current	-100		100	nA	$V_{DS}$ =0V, $V_{GS}$ =±20V
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55°C to 150°C Max.				

Mechanical Data	Die Drawing			
Chip Size <sup>(2)</sup> 7417 µm X 5018 µm				
Gate Pad Size	588 µm X 587 µm			
Source Pad Size	7043µm X 2086µm X 2			
Scribe Line Width	60 µm			
Wafer Thickness	150 µm			
Wafer Diameter	200 mm	7417 um 7043.125 un		
Gross Die	707 EA	4 m		
Source Metallization	AlCu			
Drain Metallization	Ti-Ni-Ag	2086.175 um		
Passivation	Polyimide	2086.175 um ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓ ↓		
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C			

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(1) Pulse Width tp = < 1 mS, Duty Cycle < 2%.

(2) Chip size not include scribe line.



Specific Assembly Info	Die Drawing				
Package Type	TOLL	5018.25 um			
Die Attach Method	Soft solder				
Soft Solder Composition	Pb,Sn,Ag				
Gate Wire Bonding	Al wire, 5 mil x 1	7417 um 7043.125 um			
Source Wire Bonding	Al wire, 20 mil x 5	2086.175 um			
Molding Compound Manufacturer	G700HF	2086.175 um			
Solder Plating Composition	Pure Tin				

Position		Bonding Diagram Top View	
	X (μm)	Υ (μm)	
ZERO	0	0	
ТОР	7417	5018.25	TOP S1
S1	7207.4	4797.475	
S2	164.275	2711.3	52
S3	7207.4	2306.95	55
S4	164.275	220.775	54 ZERO G2
S5	6405.859	991.425	
G1	7302.725	701.425	
G2	6713.875	114.275	

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Electrical Characteristics in F/T Test (TJ at 25 ℃)						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I <sub>DSS</sub>	Drain-to-Source Leakage Current		_	1	μA	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V
I <sub>GSSF</sub>	Gate-to-Source Leakage Current	_	_	100	nA	$V_{DS} = 0V, V_{GS} = +20V$
I <sub>GSSR</sub>	Gate-to-Source Leakage Current	-100	—	_	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =-20V
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	100	_	_	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	100	_	_	V	$V_{GS}$ =0V, $I_D$ =1mA
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance			1.4	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =20A
V <sub>GS (th)</sub>	Gate Threshold Voltage	2		4	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA
V <sub>SD</sub>	Body Diode Forward Voltage			1.1	V	$V_{GS}$ =0V, $I_{SD}$ =10A
I <sub>AS</sub>	Avalanche Current				А	$V_{DD}$ =50V, $V_{GS}$ =10V, R <sub>G</sub> =25 $\Omega$ , L=0.1mH
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55		150	°C	

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